## Notice of References Cited Application/Control No. 10/629,753 Examiner Hien N Nguyen Applicant(s)/Patent Under Reexamination KIM ET AL Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	4	US-5,825,710	10-1998	Jeng et al.	365/230.03
	В	US-6,009,036	12-1999	Takasugi, Atsushi	365/230.01
	O	US-6,069,829	05-2000	Komai et al.	365/201
	D	US-6,445,642	09-2002	Murakami, Naoki	365/233
	ш	US-6,617,842	09-2003	Nishikawa et al.	324/158.1
	F	US-			
	G	US-			
	Н	US-			
	l	US-			
	J	US-			
	К	US-		· · · · · · · · · · · · · · · · · · ·	
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	x				

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